TOSHIBA Transistor Silicon PNP Epitaxial Type

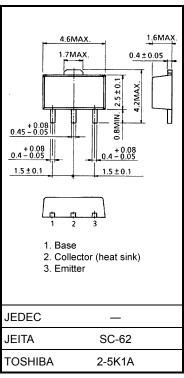
# 2SA2060

High-Speed Switching Applications DC-DC Converter Applications Strobe Applications

- High DC current gain:  $h_{FE} = 200$  to 500 (IC = -0.5 A)
- Low collector-emitter saturation voltage:  $V_{CE}$  (sat) = -0.2 V (max)
- High-speed switching: tf = 90 ns (typ.)

### Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V <sub>CBO</sub>	-50	V	
Collector-emitter voltage		V <sub>CEO</sub>	-50	V	
Emitter-base voltage		V <sub>EBO</sub>	-7	V	
Collector current	DC	Ι <sub>C</sub>	-2.0	А	
	Pulse	I <sub>CP</sub>	-3.5		
Base current		Ι <sub>Β</sub>	-200	mA	
Collector power dissipation	t = 10 s	P <sub>C</sub>	2.5	W	
	DC	(Note 1)	1.0		
Junction temperature		Тj	150	°C	
Storage temperature range		T <sub>stg</sub>	-55 to 150	°C	



Weight: 0.05 g (typ.)

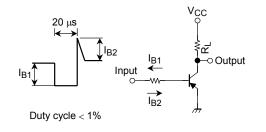
Note 1: Mounted on an FR4 board (glass epoxy, 1.6 mm thick, Cu area:  $645 \text{ mm}^2$ )

## **Electrical Characteristics (Ta = 25°C)**

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Collector cut-off current		I <sub>CBO</sub>	$V_{CB} = -50 \text{ V}, \text{ I}_{E} = 0$	-	_	-100	nA	
Emitter cut-off current		I <sub>EBO</sub>	V <sub>EB</sub> = -7 V, I <sub>C</sub> = 0	_	_	-100	nA	
Collector-emitter breakdown voltage		V (BR) CEO	I <sub>C</sub> = −10 mA, I <sub>B</sub> = 0	-50	_	_	V	
DC current gain		h <sub>FE</sub> (1)	V <sub>CE</sub> = -2 V, I <sub>C</sub> = -0.3 A	200	—	500		
		h <sub>FE</sub> (2)	V <sub>CE</sub> = -2 V, I <sub>C</sub> = -1.0 A	100	_	_		
Collector-emitter saturation voltage		V <sub>CE (sat)</sub>	I <sub>C</sub> = -1.0 A, I <sub>B</sub> = -0.033 A	_	_	-0.2	V	
Base-emitter saturation voltage		V <sub>BE (sat)</sub>	I <sub>C</sub> = -1.0 A, I <sub>B</sub> = -0.033 A	_	_	-1.1	V	
Collector output capacitance		C <sub>ob</sub>	V <sub>CB</sub> = -10 V, I <sub>E</sub> = 0, f = 1 MHz	_	20	_	pF	
Switching time	Rise time	t <sub>r</sub>	See Figure 1 circuit diagram.	_	60	_	ns	
	Storage time	t <sub>stg</sub>	V <sub>CC</sub> ≈ −30 V, R <sub>L</sub> = 30 Ω	_	250	—		
	Fall time	t <sub>f</sub>	−I <sub>B1</sub> = I <sub>B2</sub> = −33 mA	_	90	—		

Unit: mm

# Marking



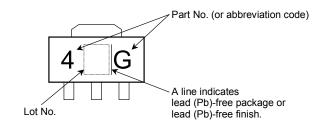
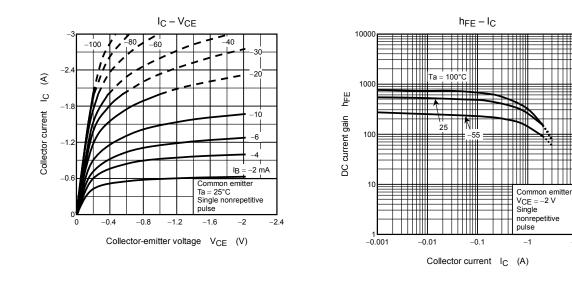
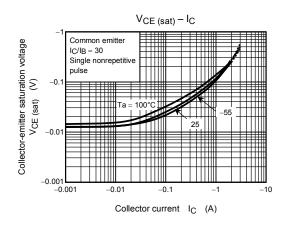


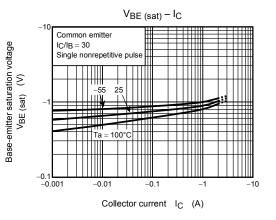
Figure 1 Switching Time Test Circuit & Timing Chart

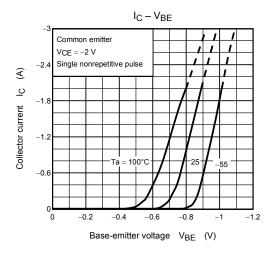
# **TOSHIBA**

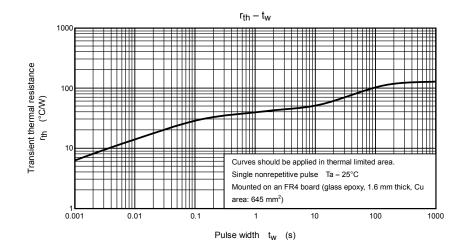
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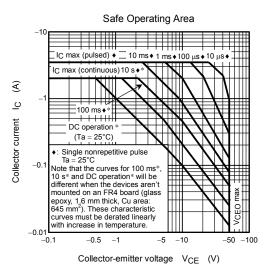












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